

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/791,815	FUJISAWA ET AL.
	<b>Examiner</b> David Buttner	<b>Art Unit</b> 1712

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
west	12/5/2005	DB
east	12/5/2005	DB
chem ab	12/5/2005	DB

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner